A teaching experimental system for defect localisation based on frequency analysis in a thermal context

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Auteur	Perez, Laetitia [1], Vergnaud, Alban [2], Autrique, Laurent [3]
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Résumé en anglais	The aim of this paper is to present a newly developed pedagogical demonstrator. It is intended for students which study automated systems and computer engineering). This experimental device can be used as a support to illustrate the course on the identification of systems and more precisely to underline the interest of frequency analysis. It can be obviously implemented as part of a Master's course allowing to deepen concepts specific to signal processing, filtering or even identification and diagnosis. It is mainly concerned with the teaching of information technology and information systems.
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